Search	Note:	S



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/042,068_	WAUKE, TOMOKUNI	
Examiner	Art Unit	
Dang D. Le	2834	

	SEAR	CHED	
Class	Subclass	Date	Examiner
310	49R 156.01- 156.84		
	152 10 46		
	216 254		
	185		
	255 258 259	7/11/2006	DL
	-0.		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
all	all	7/11/2006	DL

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	DATE	EXMR
interference search included	7/11/2006	DL